

Philips Components

Data sheet	
status	Product specification
date of issue	March 1991
Replaces BUK426-50A/B	

BUK426-60A/B

PowerMOS transistor

T-39-11

GENERAL DESCRIPTION

N-channel enhancement mode field-effect power transistor in a plastic full pack envelope. The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in automotive and general purpose switching applications.

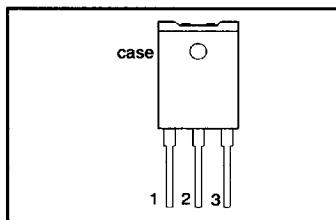
PINNING - SOT199

PIN	DESCRIPTION
1	gate
2	drain
3	source
case	isolated

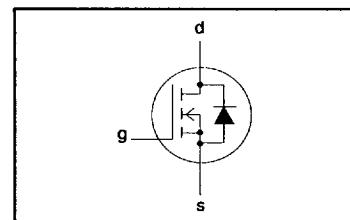
QUICK REFERENCE DATA

SYMBOL	PARAMETER	BUK426	MAX.	MAX.	UNIT
V_{DS}	Drain-source voltage	-60A	-60B	60	V
I_D	Drain current (DC)	60	60	60	A
P_{tot}	Total power dissipation	30	30	30	W
$R_{DS(on)}$	Drain-source on-state resistance	45	45	45	Ω
		0.028	0.03	0.03	

PIN CONFIGURATION



SYMBOL



LIMITING VALUES

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.		UNIT	
V_{DS}	Drain-source voltage	$R_{GS} = 20 \text{ k}\Omega$	-	60		V	
	Drain-gate voltage		-	60			
	$\pm V_{GS}$		-	30			
I_D	Drain current (DC)	$T_{hs} = 25^\circ\text{C}$	-	-60A		A	
	Drain current (DC)		-	30			
	I_{DM}		-	19			
I_{DM}	Drain current (pulse peak value)	$T_{hs} = 100^\circ\text{C}$	-	19		A	
			-	120			
			-	120			
P_{tot}	Total power dissipation	$T_{hs} = 25^\circ\text{C}$	-	45		W	
	Storage temperature		-	150			
	Junction Temperature		-	150			

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THERMAL RESISTANCES

From junction to heatsink	with heatsink compound	$R_{th,j-hs} = 2.8 \text{ K/W}$
From junction to ambient	-	$R_{th,j-a} = 35 \text{ K/W}$

STATIC CHARACTERISTICS $T_{hs} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA}$	60	-	-	V
$V_{GS(TO)}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 1 \text{ mA}$	2.1	3.0	4.0	V
I_{DSS}	Zero gate voltage drain current	$V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}; T_J = 25^\circ\text{C}$	-	1	10	μA
I_{DS}	Zero gate voltage drain current	$V_{DS} = 60 \text{ V}; V_{GS} = 0 \text{ V}; T_J = 125^\circ\text{C}$	-	0.1	1.0	mA
I_{GSS}	Gate source leakage current	$V_{GS} = \pm 30 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nA
$R_{DS(on)}$	Drain-source on-state resistance	$V_{GS} = 10 \text{ V}; BUK426-60A$ $I_D = 29 \text{ A} \quad BUK426-60B$	-	0.024	0.028	Ω
			-	0.027	0.03	Ω

DYNAMIC CHARACTERISTICS $T_{hs} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g_{fs}	Forward transconductance	$V_{DS} = 25 \text{ V}; I_D = 29 \text{ A}$	17	22	-	S
C_{iss}	Input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$	-	1500	2000	pF
C_{oss}	Output capacitance		-	800	1000	pF
C_{rss}	Feedback capacitance		-	270	400	pF
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 30 \text{ V}; I_D = 3 \text{ A}; V_{GS} = 10 \text{ V}$	-	20	30	ns
t_r	Turn-on rise time		-	70	100	ns
$t_{d(off)}$	Turn-off delay time	$R_{GS} = 50 \Omega; R_{gen} = 50 \Omega$	-	170	220	ns
t_f	Turn-off fall time		-	120	160	ns
L_d	Internal drain inductance	Measured from drain lead 6 mm from package to centre of die	-	5	-	nH
L_s	Internal source inductance	Measured from source lead 6 mm from package to source bond pad	-	12.5	-	nH

ISOLATION $T_{hs} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
V_{isol}	Repetitive peak voltage from all three terminals to external heatsink	$R.H. \leq 65\% ; \text{clean and dustfree}$	-	-	2500	V
C_{isol}	Capacitance from T2 to external heatsink	$f = 1 \text{ MHz}$	-	22	-	pF

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REVERSE DIODE LIMITING VALUES AND CHARACTERISTICS

 $T_{hs} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{DR}	Continuous reverse drain current	-	-	-	30	A
I_{DRM}	Pulsed reverse drain current	-	-	-	120	A
V_{SD}	Diode forward voltage	$I_F = 30 \text{ A}; V_{GS} = 0 \text{ V}$	-	1.4	1.7	V
t_{rr}	Reverse recovery time	$I_F = 30 \text{ A}; -dI_F/dt = 100 \text{ A}/\mu\text{s}$	-	80	-	ns
Q_{rr}	Reverse recovery charge	$V_{GS} = 0 \text{ V}; V_R = 30 \text{ V}$	-	0.4	-	μC

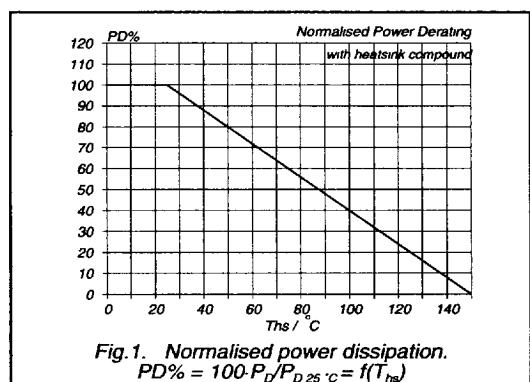


Fig. 1. Normalised power dissipation.
 $PD\% = 100 \cdot P_D / P_{D, 25^\circ\text{C}} = f(T_{hs})$

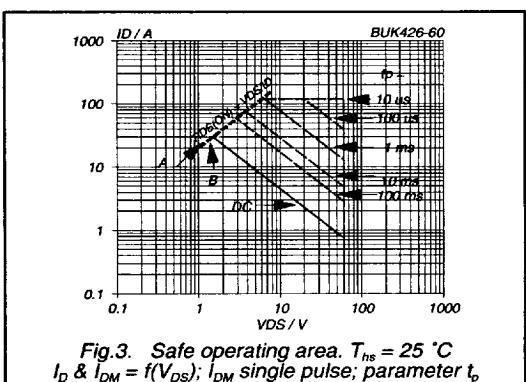


Fig. 3. Safe operating area. $T_{hs} = 25^\circ\text{C}$
 I_D & $I_{DM} = f(V_{DS})$; I_{DM} single pulse; parameter t_p

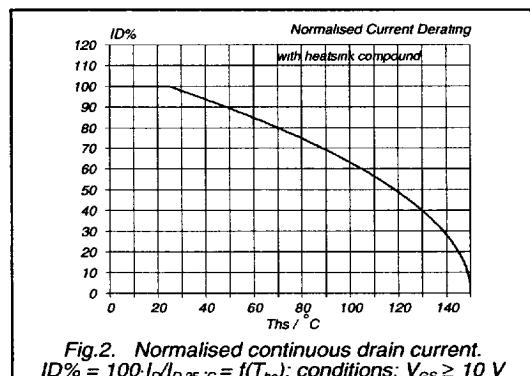


Fig. 2. Normalised continuous drain current.
 $ID\% = 100 \cdot I_D / I_{D, 25^\circ\text{C}} = f(T_{hs})$; conditions: $V_{GS} \geq 10 \text{ V}$

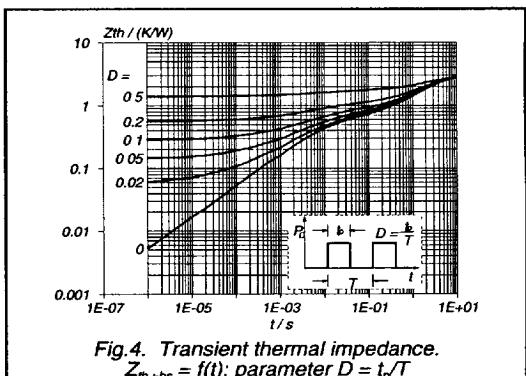


Fig. 4. Transient thermal impedance.
 $Z_{th, hs} = f(t)$; parameter $D = t_p/T$

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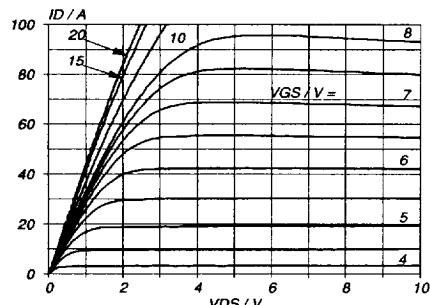


Fig.5. Typical output characteristics, $T_J = 25^\circ\text{C}$.
 $I_D = f(V_{DS})$; parameter V_{GS}

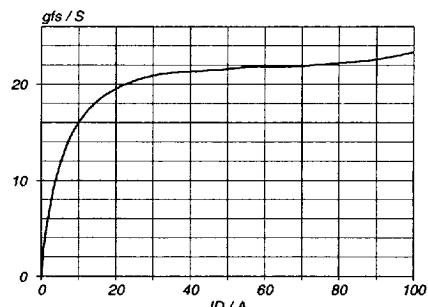


Fig.8. Typical transconductance, $T_J = 25^\circ\text{C}$.
 $g_{fs} = f(I_D)$; conditions: $V_{DS} = 25\text{ V}$

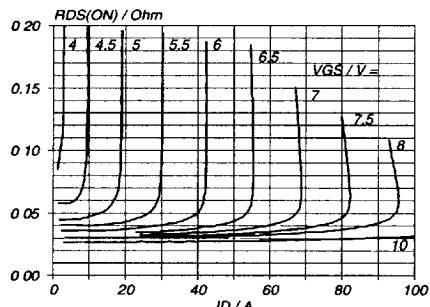


Fig.6. Typical on-state resistance, $T_J = 25^\circ\text{C}$.
 $R_{DS(ON)} = f(I_D)$; parameter V_{GS}

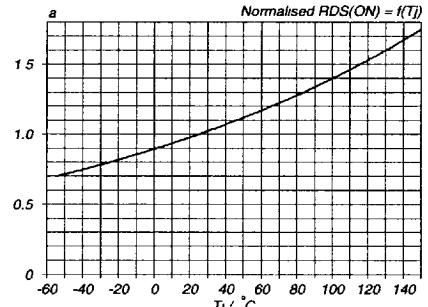


Fig.9. Normalised drain-source on-state resistance.
 $a = R_{DS(ON)}/R_{DS(ON)25^\circ\text{C}} = f(T_J)$; $I_D = 29\text{ A}$; $V_{GS} = 10\text{ V}$

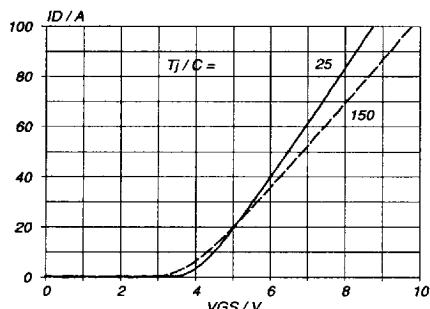


Fig.7. Typical transfer characteristics.
 $I_D = f(V_{GS})$; conditions: $V_{DS} = 25\text{ V}$; parameter T_J

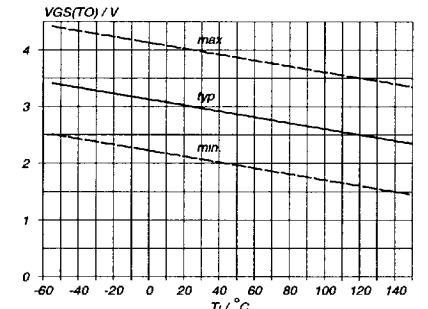


Fig.10. Gate threshold voltage.
 $V_{GS(th)} = f(T_J)$; conditions: $I_D = 1\text{ mA}$; $V_{DS} = V_{GS}$

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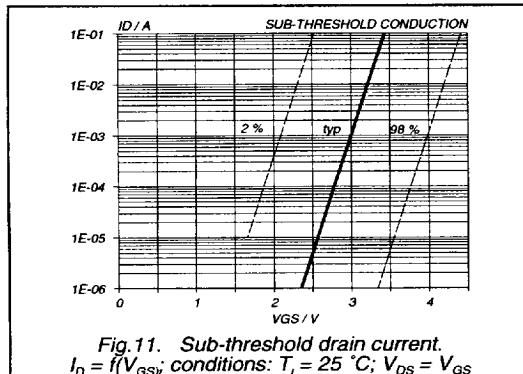


Fig.11. Sub-threshold drain current.
 $I_D = f(V_{GS})$; conditions: $T_j = 25^\circ\text{C}$; $V_{DS} = V_{GS}$

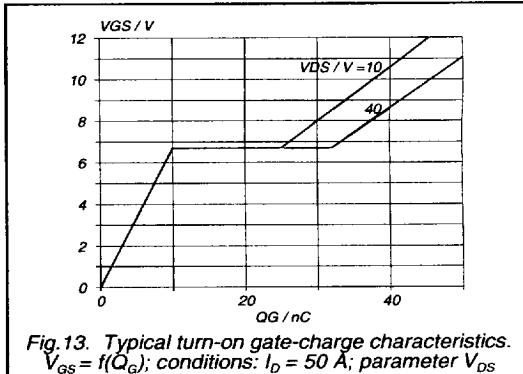


Fig.13. Typical turn-on gate-charge characteristics.
 $V_{GS} = f(Q_G)$; conditions: $I_D = 50 \mu\text{A}$; parameter V_{DS}

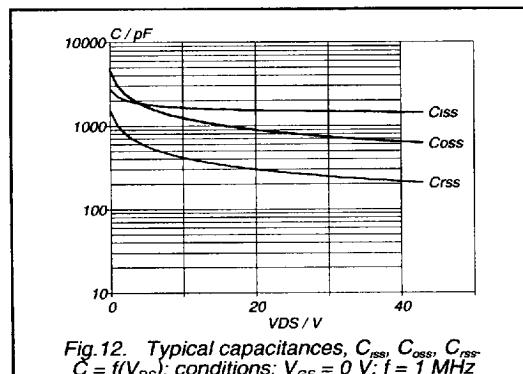


Fig.12. Typical capacitances, C_{iss} , C_{oss} , C_{rss} .
 $C = f(V_{DS})$; conditions: $V_{GS} = 0 \text{ V}$; $f = 1 \text{ MHz}$

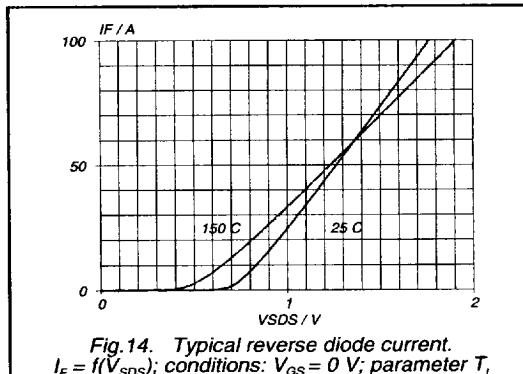


Fig.14. Typical reverse diode current.
 $I_F = f(V_{DS})$; conditions: $V_{GS} = 0 \text{ V}$; parameter T_j